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OCT 13 2006

C O N F I D E N T I A L

TO: Examiner Laurie Anne Ries / USPTO Art Unit 2176

FAX NO.: (571) 273-8300

FROM: Thomas Plunkett

RE: Applicant Initiated Interview Request Form; Appl. No. 09/944,817

DATE: October 13, 2006 Total Pages : 2

Original will follow by mail: No

If you do not receive all of the pages, please call Elaine Fischman at 415.362.3800.

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OCT 13 2006

Approved for use through 07/31/2006. OMB 0651-0031
U.S. Patent and Trademark Office: U.S. DEPARTMENT OF COMMERCE

Applicant Initiated Interview Request Form

Application No.: 09/944,817 First Named Applicant: Gene Golovchinsky
 Examiner: Laurie Ries Art Unit: 2176 Status of Application: pending

Tentative Participants:

(1) Thomas K. Plunkett (2) Karl F. Kenna
 (3) _____ (4) _____

Proposed Date of Interview: 10/16/2006 Proposed Time: 2:00 PM (AM/PM)

Type of Interview Requested:

(1) Telephonic (2) Personal (3) Video Conference

Exhibit To Be Shown or Demonstrated: YES NO
 If yes, provide brief description: _____

Issues To Be Discussed

Issues (Rej., Obj., etc)	Claims/ Fig. #s	Prior Art	Discussed	Agreed	Not Agreed
(1) <u>Rej.</u>	<u>Claim 1</u>	<u>Reber</u>	<input type="checkbox"/>	<input type="checkbox"/>	<input type="checkbox"/>
(2) _____	_____	_____	<input type="checkbox"/>	<input type="checkbox"/>	<input type="checkbox"/>
(3) _____	_____	_____	<input type="checkbox"/>	<input type="checkbox"/>	<input type="checkbox"/>
(4) _____	_____	_____	<input type="checkbox"/>	<input type="checkbox"/>	<input type="checkbox"/>
[] Continuation Sheet Attached					

Brief Description of Arguments to be Presented:

Discussion of Office Action of 8/08/2006 regarding the patentability of Claim 1
over the prior art cited by the office action.

An interview was conducted on the above-identified application on _____.

NOTE: This form should be completed by applicant and submitted to the examiner in advance of the interview (see MPEP § 713.01).

This application will not be delayed from issue because of applicant's failure to submit a written record of this interview. Therefore, applicant is advised to file a statement of the substance of this interview (37 CFR 1.133(b)) as soon as possible.

 Applicant/Applicant's Representative Signature

 Examiner/SPE Signature

Thomas K. Plunkett

 Typed/Printed Name of Applicant or Representative

57,253

 Registration Number, if applicable

This collection of information is required by 37 CFR 1.133. The information is required to obtain or retain a benefit by the public which is to file (and by the USPTO to process) an application. Confidentiality is governed by 35 U.S.C. 122 and 37 CFR 1.11 and 1.14. This collection is estimated to take 21 minutes to complete, including gathering, preparing, and submitting the completed application form to the USPTO. Time will vary depending upon the individual case. Any comments on the amount of time you require to complete this form and/or suggestions for reducing this burden, should be sent to the Chief Information Officer, U.S. Patent and Trademark Office, U.S. Department of Commerce, P.O. Box 1450, Alexandria, VA 22313-1450. DO NOT SEND FEES OR COMPLETED FORMS TO THIS ADDRESS. SEND TO: Commissioner for Patents, P.O. Box 1450, Alexandria, VA 22313-1450.

If you need assistance in completing the form, call 1-800-PTO-9199 and select option 2.